

**Search Notes****Application/Control No.**

09/975,912

**Examiner**

Afsar M. Qureshi

**Applicant(s)/Patent under Reexamination**

CHEN ET AL.

**Art Unit**

2667

**SEARCHED**

Class	Subclass	Date	Examiner
370	310.2	12/1/2005	AQ
	328		
	329		
	331		
	332		
	352		
	401		
	428		
455	442		
	445		
	422		

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST/WEST	12/1/2005	AQ
IEEE/FAST		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
Interference search included			